Total No.	of	Questions	:12]	ı
-----------	----	-----------	------	---

SEAT No. :		
[Total	No. of Pages	:3

P3377

[4959]-115

B.E. (Electronics)

a: ADVANCED MEASUREMENT SYSTEMS (2008 Course) (Semester - I) (Elective - I)

Time: 3 Hours] [Max. Marks:100

Instructions to the candidates:

- 1) Answers to the two sections should be written in separate books.
- 2) Answer Q1 or Q2, Q3 or Q4, Q5 or Q6, Q7 or Q8, Q9 or Q10, Q11 or Q12.
- 3) Use of electronic pocket calculator is allowed.
- 4) Figures to the right side indicate full marks.
- 5) Assume suitable data if necessry.

SECTION-I

- Q1) a) What is signal integrity? How to ensure signal integrity in case of RF CMOS circuits?
 - b) With the help of block schematic explain arbitrary waveform generator and give its typical application. [8]

OR

- Q2) a) How DPO differs from DSO? Give typical application of DPO. [8]
 - b) What is need of MSO? List important specifications of MSO and give typical application of MSO. [8]
- Q3) a) List and elaborate at least eight parameters to consider while selecting DSO.[8]
 - b) Give typical specifications of Logic Analyzer. Explain how it can be used in fault finding in microcontroller circuits. [10]

OR

Q4)	a) With res		n respect to DSO explain the terms [1	[0]
		i)	Math functions	
		ii)	FFT	
		iii)	Roll mode	
		iv)	Zoom mode	
		v)	Glitch mode	
	b)		n the help of functional block diagram explain working of RF sweet heterodyne spectrum analyzer?	ept [8]
Q5)	a)		at is role of Electronic measurements for Electronic Central Unit [EC n Automotive system?	[8]
	b)	Exp	lain need and use of RF modules and Ethernet in Embedded system	ns? [8]
			OR	
Q6)	a)	Exp	lain interfacing techniques for:	[8]
		i)	16X2 Graphic LCD	
		ii)	Alphanumeric Touch Screen	
	b)	Exp	lain USB and CAN bus standards required in embedded systems?	[8]
			SECTION-II	
Q7)	a)	_	lain in detail the EMI/EMC test set up for conducted and radiate ference measurement?	ted [8]
	b)		w a scheme for microwave power measurement using microwarer bridge circuit with barraters and explain the method?	ave [8]
			OR	
Q8)	a)	Drav Syst	w and elaborate the fundamental test setup for Advanced Racem.	dar [8]
	b)		at are different attenuation measurement techniques used in microwa work? Explain the schemes?	ave [8]
[40	0501_	115	2	

Explain the concept of virtual instrumentation and its benefits in test and **Q9**) a) measurements? [8] Explain the terms GPIB and SCPI of virtual instrumentation? [8] b) OR Elaborate in detail application of the virtual instrumentation for the distortion *Q10*)a) analyzer. [8] Explain the desired features of software used for virtual instruments?[8] b) *Q11)*a) Discuss the errors encountered in measurement of frequency/time period digitally? How to minimize these errors? [10]b) Explain the data logger in detail with its typical application? [8] OR Explain the concept of ADC. List various types of ADCs with important **Q12)**a) specifications and explain any one in detail? [10]Explain the different automations in digital equipments; namely auto b) polarity, auto ranging and auto zeroing? [8]

888